

FCC ID: 2ACB3-F1

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHZ})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHZ})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	1.59	1.44	1±1	2	1.58	<5	0.49127	3.00	YES
	2.441	1.38	1.37	1±1	2	1.58	<5	0.49524	3.00	YES
	2.480	1.66	1.47	1±1	2	1.58	<5	0.49918	3.00	YES
π/4-DQPSK	2.402	1.53	1.42	1±1	2	1.58	<5	0.49127	3.00	YES
	2.441	1.3	1.35	1±1	2	1.58	<5	0.49524	3.00	YES
	2.480	1.55	1.43	1±1	2	1.58	<5	0.49918	3.00	YES
8-DQPSK	2.402	1.66	1.47	1±1	2	1.58	<5	0.49127	3.00	YES
	2.441	1.47	1.40	1±1	2	1.58	<5	0.49524	3.00	YES
	2.480	1.73	1.49	1±1	2	1.58	<5	0.49918	3.00	YES
BLE1M	2.402	0.52	1.13	0±1	1	1.26	<5	0.39023	3.00	YES
	2.441	0.33	1.08	0±1	1	1.26	<5	0.39338	3.00	YES
	2.480	0.6	1.15	0±1	1	1.26	<5	0.39651	3.00	YES
BLE2M	2.402	0.28	1.07	0±1	1	1.26	<5	0.39023	3.00	YES
	2.441	0.06	1.01	0±1	1	1.26	<5	0.39338	3.00	YES
	2.480	0.31	1.07	0±1	1	1.26	<5	0.39651	3.00	YES

Conclusion:

For the max result : $0.49918 \leq 3.0$ for 1g SAR, SAR is not required.



Signature:

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